

<b>Notice of References Cited</b>	Application/Control No. 10/684,410	Applicant(s)/Patent Under Reexamination YAMAZAKI ET AL.	
	Examiner C. Melissa Koslow	Art Unit 1755	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,641,933 B1	11-2003	Yamazaki et al.	428/690
	B	US-6,300,612 B1	10-2001	Yu, Gang	250/208.1
	C	US-6,661,454 B1	12-2003	Hwang et al.	348/231.1
	D	US- 6,617,051	09-2003	H. Gashi et al	1128/1690
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zou et al, "Study on the degradation mechanism of organic light-emitting diodes (OLEDs)", Synthetic Metals 91 (1997), pp. 191 93.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.